

Applications

- Transceivers
- Multi-band Modules
- RFICs
- Microwave Components



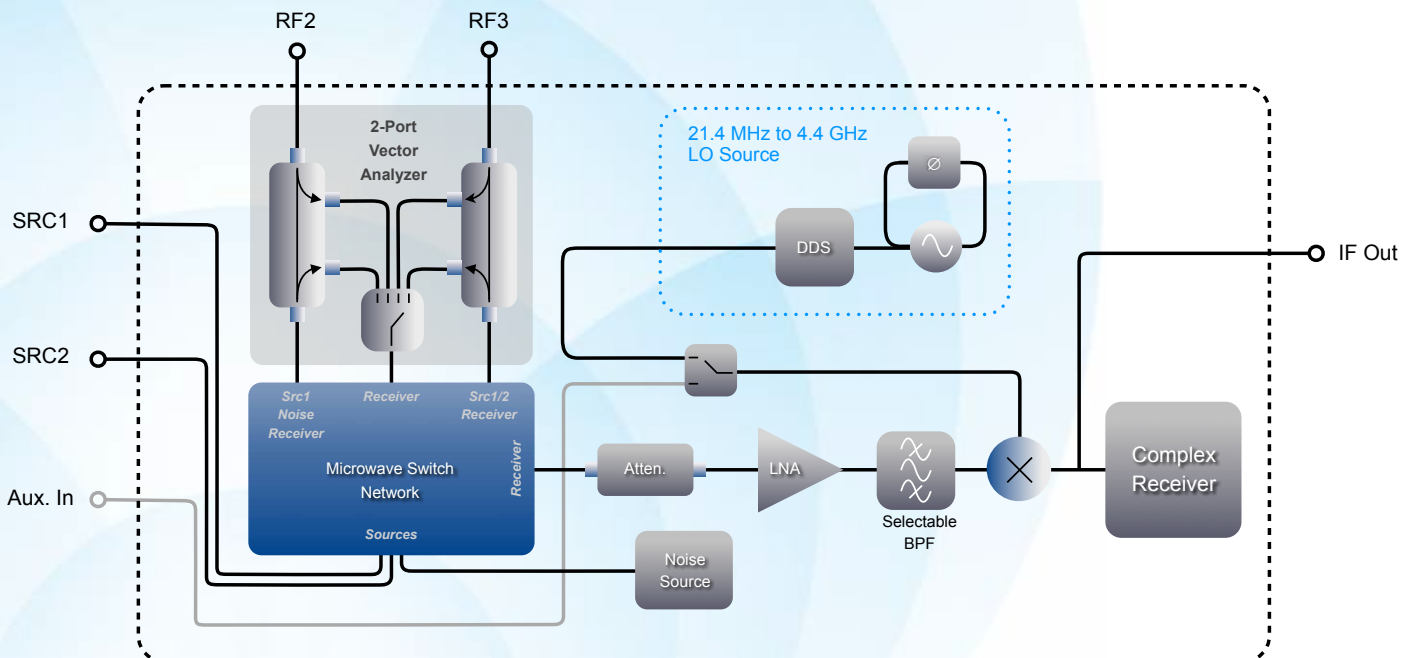
Overview

The RI8567 Test Set combines a 2-port vector analyzer and complex receiver into a single test instrument. The versatile multi-port test set interfaces with a Cassini source for direct power, harmonic, distortion, and s-parameter measurements from 100 kHz to 12 GHz. With microsecond frequency switching and signal path calibration, the RI8567 can be shared across multiple RF ports for fast, precision measurements and maximum channel utilization.

Key Features

- *S-Parameters from 100 MHz to 12 GHz*
- *Direct Power/Spectrum Measure*
- *0.1 dB Measurement Resolution*
- *Microsecond Frequency Locking*

Block Diagram



Performance

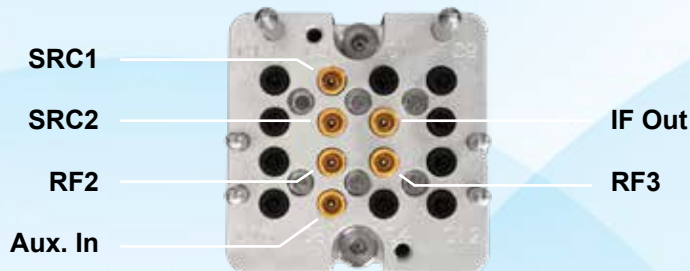
Vector Analyzer

Frequency Range	100MHz to 12GHz
Power Range	-100dBm to +30dBm
Power Resolution	±0.1dB

Receiver

Frequency Range	100kHz to 12GHz
Power Range	-115 dBm to +20 dBm
Meas. Bandwidth	7 kHz / 200kHz / 5MHz (selectable)

Inputs/Outputs



Cassini Test Systems

A versatile, high-speed, automated test solution for analog, mixed-signal, RF, and millimeter-wave devices.

Cassini provides a modular base architecture that is fully configurable via Test Instrument Modules (TIMs) to meet the needs of any IC, wafer, or module test requirement.

Each TIM contains internally-cooled, RF-shielded measurement instrumentation, signal distribution, and blind mate interfacing to provide targeted test resources and integrate to build up a complete production test platform.

Combined with Roos Instruments' integrated test software, Cassini can be configured to any application for maximum performance, true low cost of test, and the industry's fastest test times.

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